



**DIODES, SWITCHING,  
BASED ON TYPE 1N4153  
ESCC Detail Specification No. 5101/016**

**ISSUE 1  
October 2002**



	ESCC Detail Specification		PAGE ii ISSUE 1
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Pages 1 to 17

DIODES, SWITCHING,

BASED ON TYPE 1N4153

ESA/SCC Detail Specification No. 5101/016



space components  
coordination group

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**SCC**

ESA/SCC Detail Specification  
No. 5101/016


Rev. 'A'

PAGE 2

ISSUE 2


**DOCUMENTATION CHANGE NOTICE**

Rev. Letter	Rev. Date	Reference	CHANGE Item	Approved DCR No.
		This Issue supersedes Issue 1 and incorporates all modifications defined in the following DCR's:-		
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		Table 1(a)	: Table standardised	21021
		Table 1(b)	: No. 4, symbol corrected	23476
		Para. 2	: Reference to ESA/SCC Basic Specification No. 23500 added	21025
		Para. 4.2.2	: PIND deviation entry standardised	21043
		Para. 4.2.3	: Reference to Radiographic Inspection deleted	21049
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		Table 6	: Format and numbering standardised	23476
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		P2. DCN		None
		P3. T of C	: New Para 1.7 entry added	21083
		P5. Para. 1.7	: New Para. 1.7 entry added	21083

 <b>SCC</b>	ESA/SCC Detail Specification No. 5101/016	Rev. 'A'	PAGE 3 ISSUE 2
--	--	----------	-------------------

**TABLE OF CONTENTS**

	<u>Page</u>
<b>1. GENERAL</b>	<b>5</b>
1.1 Scope	5
1.2 Component Type Variants	5
1.3 Maximum Ratings	5
1.4 Parameter Derating Information	5
1.5 Physical Dimensions	5
1.6 Functional Diagram	5
1.7 High Temperature Test Precautions	5
<b>2. APPLICABLE DOCUMENTS</b>	<b>9</b>
<b>3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS</b>	<b>9</b>
<b>4. REQUIREMENTS</b>	<b>9</b>
4.1 General	9
4.2 Deviations from Generic Specification	9
4.2.1 Deviations from Special In-process Controls	9
4.2.2 Deviations from Final Production Tests	9
4.2.3 Deviations from Burn-in and Electrical Measurements	9
4.2.4 Deviations from Qualification Tests	9
4.2.5 Deviations from Lot Acceptance Tests	9
4.3 Mechanical Requirements	10
4.3.1 Dimension Check	10
4.3.2 Weight	10
4.3.3 Terminal Strength	10
4.4 Materials and Finishes	10
4.4.1 Case	10
4.4.2 Lead Material and Finish	10
4.5 Marking	10
4.5.1 General	10
4.5.2 Lead Identification	10
4.5.3 The SCC Component Number	11
4.5.4 Traceability Information	11
4.5.5 Marking of Small Components	11
4.6 Electrical Measurements	11
4.6.1 Electrical Measurements at Room Temperature	11
4.6.2 Electrical Measurements at High and Low Temperatures	11
4.6.3 Circuits for Electrical Measurements	11
4.7 Burn-in Tests	11
4.7.1 Parameter Drift Values	11
4.7.2 Conditions for Burn-in	11
4.7.3 Electrical Circuits for Burn-in	11
4.8 Environmental and Endurance Tests	15
4.8.1 Electrical Measurements on Completion of Environmental Tests	15
4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests	15
4.8.3 Conditions for Operating Life Tests	15
4.8.4 Electrical Circuits for Operating Life Tests	15
4.8.5 Conditions for High Temperature Storage Test	15

	<p style="text-align: center;">ESA/SCC Detail Specification No. 5101/016</p>		<p>PAGE 4 ISSUE 2</p>
---	--	--	---------------------------

**TABLES**


		<u>Page</u>
1(a)	Type Variants	6
1(b)	Maximum Ratings	6
2	Electrical Measurements at Room Temperature - D.C. Parameters	12
	Electrical Measurements at Room Temperature - A.C. Parameters	12
3	Electrical Measurements at High and Low Temperatures	13
4	Parameter Drift Values	13
5	Conditions for Burn-in and Operating Life Test	14
6	Electrical Measurements at Intermediate Points and on Completion of Endurance Tests	16

**FIGURES**

1	Parameter Derating Information	7
2	Physical Dimensions	8
3	Functional Diagram	8
4	Circuits for Electrical Measurements	13
5	Electrical Circuit for Burn-in and Operating Life Test	14

**APPENDICES (Applicable to specific Manufacturers only)**

'A'	Agreed Deviations for Unitrode (USA)	17
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	<p style="text-align: center;">ESA/SCC Detail Specification No. 5101/016</p>	<p style="text-align: center;">Rev. 'A'</p>	<p>PAGE 5 ISSUE 2</p>
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1. **GENERAL**

1.1 **SCOPE**

This specification details the ratings, physical and electrical characteristics, test and inspection data for Diodes, Switching, based on Type 1N4153. It shall be read in conjunction with ESA/SCC Generic Specification No. 5000, the requirements of which are supplemented herein.

1.2 **COMPONENT TYPE VARIANTS**

Variants of the basic type diodes specified herein, which are also covered by this specification, are given in Table 1(a).

1.3 **MAXIMUM RATINGS**

The maximum ratings, which shall not be exceeded at any time during use or storage, applicable to the diodes specified herein, are as scheduled in Table 1(b).

1.4 **PARAMETER DERATING INFORMATION**

The parameter derating information applicable to the diodes specified herein, is shown in Figure 1.

1.5 **PHYSICAL DIMENSIONS**

The physical dimensions of the diodes specified herein, are shown in Figure 2.

1.6 **FUNCTIONAL DIAGRAM**

The functional diagram, showing lead identification, of the diodes specified herein, is shown in Figure 3.

1.7 **HIGH TEMPERATURE TEST PRECAUTIONS**

For tin-lead plated or solder-dipped lead finish, all tests to be performed at a temperature that exceeds +125°C shall be carried out in 100% inert atmosphere.

**TABLE 1(a) - TYPE VARIANTS**

VARIANT	CASE	LEAD MATERIAL AND/OR FINISH
01	D035	C3 or C4

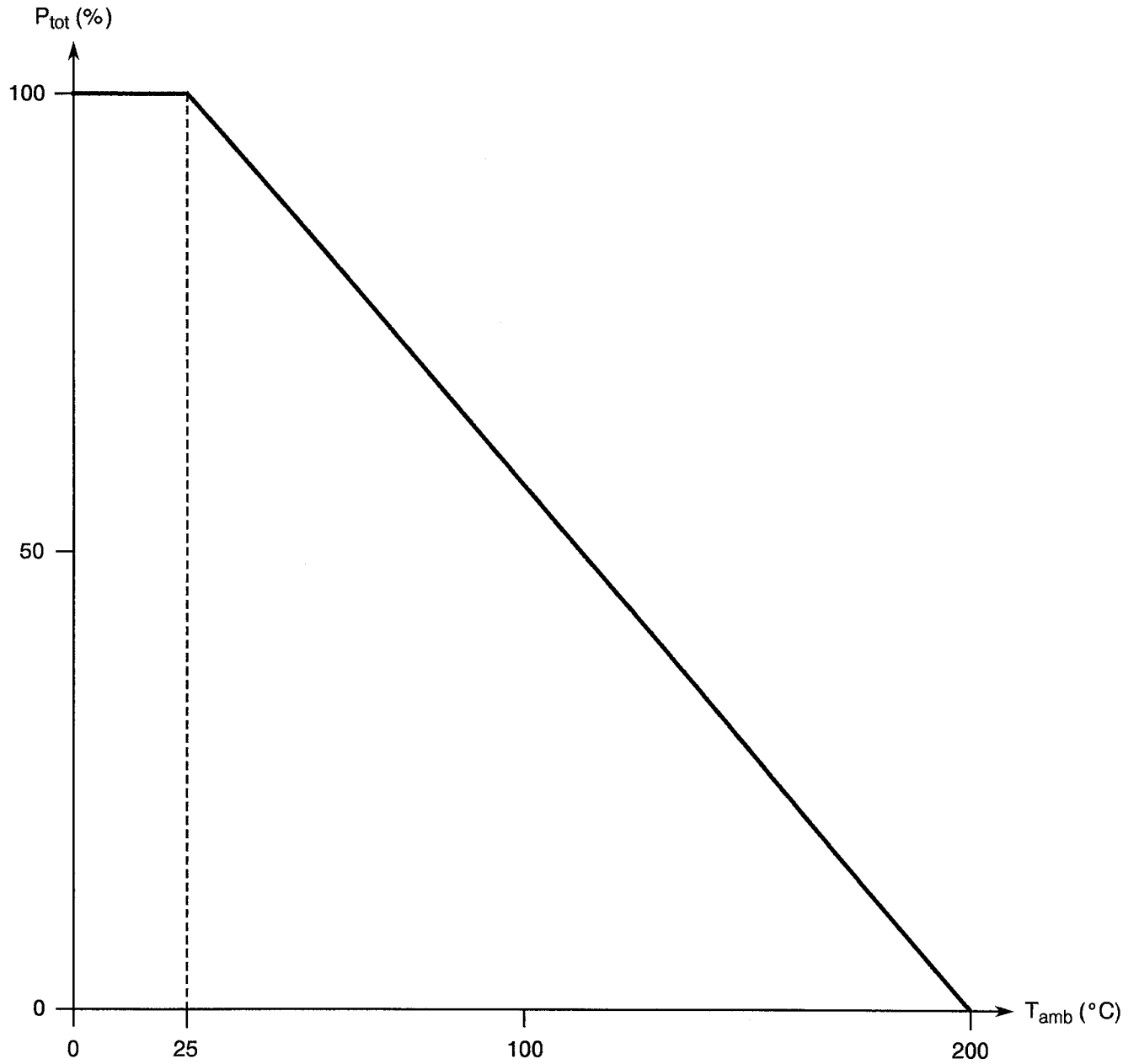
**TABLE 1(b) - MAXIMUM RATINGS**

No.	CHARACTERISTICS	SYMBOL	MAXIMUM RATING	UNIT	REMARKS
1	DC Reverse Voltage	$V_R$	-50	V	
2	Peak Reverse Voltage	$V_{RM}$	75	V	
3	Total Power Dissipation	$P_{tot}$	400	mW	
4	Operating Temperature Range	$T_{op}$	-55 to +200	°C	$T_{amb}$
5	Storage Temperature Range	$T_{stg}$	-65 to +250	°C	
6	Soldering Temperature	$T_{sol}$	+260	°C	Time: $\leq 10s$ ; Distance from case: $\geq 1.5mm$

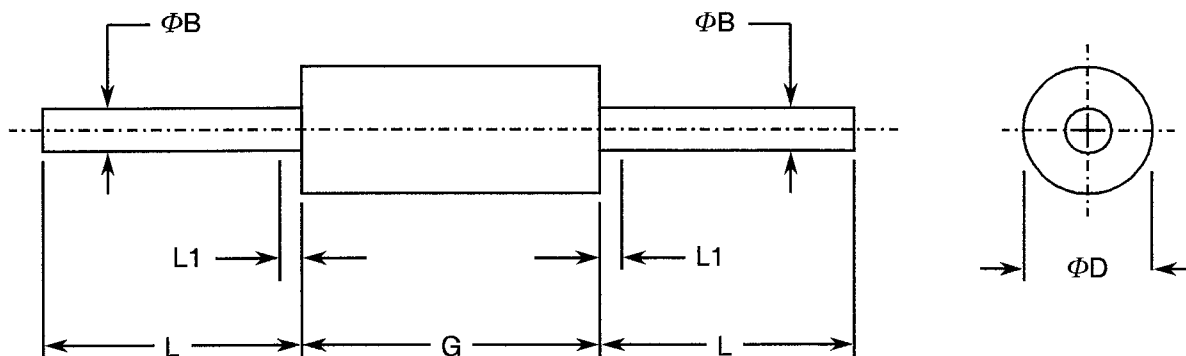




**FIGURE 1 - PARAMETER DERATING INFORMATION**



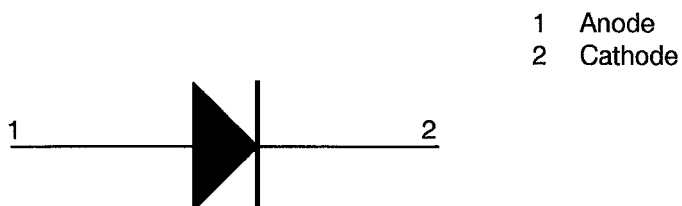
Power Dissipation versus Temperature

**FIGURE 2 - PHYSICAL DIMENSIONS**




SYMBOL	MILLIMETRES		NOTES
	MIN.	MAX.	
$\Phi B$	0.458	0.558	-
$\Phi D$	1.42	1.91	1
G	3.56	4.57	1
L	12.70	-	-
L1	-	1.27	2

**NOTES**

1. Package contour optional within cylinder of diameter  $\Phi D$  and length G. Slugs, if any, shall be included within this cylinder but shall not be subject to the minimum limit of  $\Phi D$ .
2. Lead diameter not controlled in this zone to allow for flash, lead finish build-up, and minor irregularities other than slugs.

**FIGURE 3 - FUNCTIONAL DIAGRAM**

**NOTES**

1. The cathode end shall be marked with a coloured ring.

 	ESA/SCC Detail Specification No. 5101/016		PAGE 9 ISSUE 2
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**2. APPLICABLE DOCUMENTS**

The following documents form part of this specification and shall be read in conjunction with it:-

- (a) ESA/SCC Generic Specification No. 5000 for Discrete Semiconductors.
- (b) MIL-STD-750, Test Methods and Procedures for Semiconductor Devices.
- (c) ESA/SCC Basic Specification No. 23500, Requirements for Lead Materials and Finishes for Space Application.

**3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS**

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply.

**4. REQUIREMENTS**

**4.1 GENERAL**

The complete requirements for procurement of the diodes specified herein shall be as stated in this specification and ESA/SCC Generic Specification No. 5000 for Discrete Semiconductors. Deviations from the Generic Specification, applicable to this Detail Specification only, are listed in Para. 4.2.

Deviations from the applicable Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESA/SCC requirements and do not affect the components' reliability, are listed in the appendices attached to this specification.

**4.2 DEVIATIONS FROM GENERIC SPECIFICATION**

**4.2.1 Deviations from Special In-process Controls**

None.

**4.2.2 Deviations from Final Production Tests (Chart II)**

- (a) Para. 9.2.1, Bond Strength Test: Not applicable.
- (b) Para. 9.2.2, Die Shear Test: Not applicable.
- (b) Para. 9.7, Particle Impact Noise Detection (PIND) Test: Not applicable.

**4.2.3 Deviations from Burn-in and Electrical Measurements (Chart III)**



- (a) Para 7.1.1(a), H.T.R.B. Test: Not applicable.

**4.2.4 Deviations from Qualification Tests (Chart IV)**

- (a) Para. 9.2.3, Bond Strength Test: Not applicable.
- (b) Para. 9.2.4, Die Shear Test: Not applicable.

**4.2.5 Deviations from Lot Acceptance Tests (Chart V)**

None.

 	<p style="text-align: center;">ESA/SCC Detail Specification No. 5101/016</p>	<p>PAGE 10 ISSUE 2</p>
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#### 4.3 MECHANICAL REQUIREMENTS

##### 4.3.1 Dimension Check

The dimensions of the diodes specified herein shall be checked. They shall conform to those shown in Figure 2.

##### 4.3.2 Weight

The maximum weight of the diodes specified herein shall be 0.2 grammes.

##### 4.3.3 Terminal Strength

The requirements for terminal strength testing are specified in Section 9 of ESA/SCC Generic Specification No. 5000. The test conditions shall be as follows:-

Test Condition : 'A'.

Applied Force : 5.0 Newtons.

Duration : 10 seconds.

#### 4.4 MATERIALS AND FINISHES

The materials and finishes shall be as specified herein. Where a definite material is not specified, a material which will enable the diodes specified herein to meet the performance requirements of this specification shall be used. Acceptance or approval of any constituent material does not guarantee acceptance of the finished product.

##### 4.4.1 Case

Glass, hermetically sealed.

##### 4.4.2 Lead Material and Finish

The lead material shall be Type 'C' with Type '3' or Type '4' finish in accordance with the requirements of ESA/SCC Basic Specification No. 23500.

#### 4.5 MARKING

##### 4.5.1 General

The marking of all components delivered to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 21700. Each component shall be marked in respect of:-

(a) Lead Identification.

(b) The SCC Component Number.

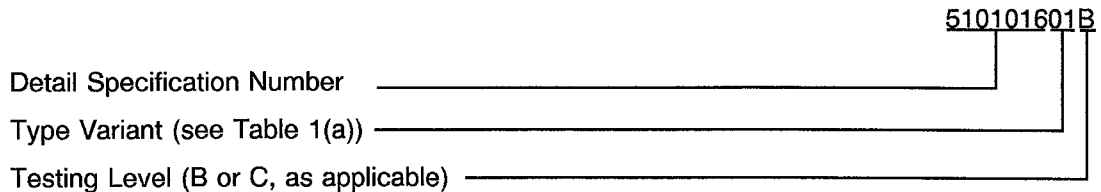
(c) Traceability Information.

##### 4.5.2 Lead Identification

Lead identification shall be as shown in Figures 2 and 3.

4.5.3 The SCC Component Number

Each component shall bear the SCC Component Number which shall be constituted and marked as follows:



4.5.4 Traceability Information

Each component shall be marked in respect of traceability information as defined in ESA/SCC Basic Specification No. 21700.

4.5.5 Marking of Small Components

When it is considered that the component is too small to accommodate the marking as specified above, as much as space permits shall be marked. The order of precedence shall be as follows:-

- (a) Lead identification.
- (b) The SCC Component number.
- (c) Traceability information.

The marking information in full shall accompany each component in its primary package.

4.6 ELECTRICAL MEASUREMENTS

4.6.1 Electrical Measurements at Room Temperature

The parameters to be measured at room temperature are scheduled in Table 2. The measurements shall be performed at  $T_{amb} = +22 \pm 3 \text{ }^\circ\text{C}$ .

4.6.2 Electrical Measurements at High and Low Temperatures

The parameters to be measured at high and low temperatures are scheduled in Table 3.

4.6.3 Circuits for Electrical Measurements

Circuits for use in performing electrical measurements listed in Tables 2 and 3 are shown in Figure 4.

4.7 BURN-IN TESTS

4.7.1 Parameter Drift Values

The parameter drift values applicable to burn-in are specified in Table 4 of this specification. Unless otherwise stated, measurements shall be performed at  $T_{amb} = +22 \pm 3 \text{ }^\circ\text{C}$ . The parameter drift values ( $\Delta$ ) applicable to the scheduled parameters shall not be exceeded. In addition to these drift value requirements for a given parameter, the appropriate limit value specified in Table 2 shall not be exceeded.

4.7.2 Conditions for Burn-in

The requirements for Burn-in are specified in Section 7 of ESA/SCC Generic Specification No. 5000. The conditions for Burn-in shall be as specified in Table 5 of this specification.

4.7.3 Electrical Circuits for Burn-in

Circuits for use in performing the Burn-in tests are shown in Figure 5 of this specification.

**TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - D.C. PARAMETERS**

No.	CHARACTERISTICS	SYMBOL	MIL-STD-750 TEST METHOD	TEST CONDITIONS	LIMITS		UNIT
					MIN.	MAX.	
1	DC Forward Voltage	$V_F$	4011	$I_F = 20\text{mA}$	0.74	0.88	V
2	DC Reverse Current	$I_R$	4016	$V_R = -50\text{V}$	-	0.05	$\mu\text{A}$
3	DC Breakdown Reverse Voltage	$V_{(BR)}$	4021	$I_R = 5.0\mu\text{A}$	75	-	V

**TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - A.C. PARAMETERS**

No.	CHARACTERISTICS	SYMBOL	MIL-STD-750 TEST METHOD	TEST CONDITIONS	LIMITS		UNIT
					MIN.	MAX.	
1	Capacitance	C	4001	$V_R = 0$ $f = 1.0\text{MHz}$	-	2.0	pF
2	Reverse Current Recovery Time	$t_{rr}$	4031, Condition 'B'	$I_F = -I_{RM} = 10\text{mA}$ $i_{rr} = 1.0\text{mA}$	-	4.0	ns

**NOTES**

1. Measurements shall be performed on a sample basis, LTPD7.

**TABLE 3 - ELECTRICAL MEASUREMENTS AT HIGH AND LOW TEMPERATURES**

No.	CHARACTERISTICS	SYMBOL	MIL-STD-750 TEST METHOD	TEST CONDITIONS	LIMITS		UNIT
					MIN.	MAX.	
2	DC Reverse Current	$I_R$	4016	$T_{amb} = +150^{\circ}C$ $V_R = -50V$	-	0.05	mA

**FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS**

Not applicable

**TABLE 4 - PARAMETER DRIFT VALUES**

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITIONS	CHANGE LIMITS	UNIT
1	DC Forward Voltage	$V_F$	As per Table 2	As per Table 2	$\pm 100$	mV
2	DC Reverse Current	$I_R$	As per Table 2	As per Table 2	$\pm 100$ or (1) $\pm 5.0$	% nA

**NOTES**

1. Whichever is the greater.


**TABLE 5 - CONDITIONS FOR BURN-IN AND OPERATING LIFE TEST**

No.	CHARACTERISTICS	SYMBOL	CONDITION	UNIT
1	Working Voltage	$V_{WK}$	50V(PK)	V
2	Average Rectified Current	$I_O$	150	mA
3	Frequency	f	50 to 60	Hz

**FIGURE 5 - ELECTRICAL CIRCUIT FOR BURN-IN AND OPERATING LIFE TEST**

Not applicable.



	<p style="text-align: center;">ESA/SCC Detail Specification No. 5101/016</p>	<p style="text-align: right;">PAGE 15 ISSUE 2</p>
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4.8 ENVIRONMENTAL AND ENDURANCE TESTS (CHARTS IV AND V OF ESA/SCC GENERIC SPECIFICATION NO. 5000)

4.8.1 Electrical Measurements on Completion of Environmental Tests

The parameters to be measured on completion of environmental tests are scheduled in Table 2. Unless otherwise stated, the measurements shall be performed at  $T_{amb} = +22 \pm 3^{\circ}\text{C}$ .

4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests

The parameters to be measured at intermediate points and on completion of endurance tests are scheduled in Table 6. Unless otherwise stated, the measurements shall be performed at  $T_{amb} = +22 \pm 3^{\circ}\text{C}$ .

4.8.3 Conditions for Operating Life Tests (Part of Endurance Testing)

The requirements for operating life testing are specified in Section 9 of ESA/SCC Generic Specification No. 5000. The conditions for operating life testing shall be the same as specified in Table 5 for the burn-in test.

4.8.4 Electrical Circuits for Operating Life Tests

Not applicable.

4.8.5 Conditions for High Temperature Storage Test (Part of Endurance Testing)

The requirements for the high temperature storage test are specified in ESA/SCC Generic Specification No. 5000. The temperature to be applied shall be the maximum storage temperature specified in Table 1(b) of this specification.

**TABLE 6 - ELECTRICAL MEASUREMENTS AT INTERMEDIATE POINTS  
AND ON COMPLETION OF ENDURANCE TESTS**

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITIONS	LIMITS		UNIT
					MIN.	MAX.	
1	DC Forward Voltage	$V_F$	As per Table 2	As per Table 2	-	0.88	V
2	DC Reverse Current	$I_R$	As per Table 2	As per Table 2	-	50	$\mu A$

**SCC**ESA/SCC Detail Specification  
No. 5101/016

PAGE 17

ISSUE 2

**APPENDIX 'A'**Page 1 of 1**AGREED DEVIATIONS FOR UNITRODE (USA)**

ITEMS AFFECTED	DESCRIPTION OF DEVIATIONS
Para. 4.2.2 Para. 4.2.4	Internal (pre-encapsulation) Visual Inspection may be performed to MIL-STD-750, Test Method 2074.
Para. 4.2.2 Para. 4.2.3 Para. 4.2.4 Para. 4.2.5	External Visual Inspection may be performed to MIL-STD-750, Test Method 2071.
Para. 4.2.3	Radiographic Inspection may be performed to MIL-STD-750, Test Method 2076.